PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Takashi IGARASHI et al.

Group Art Unit: 3723

Application No.: 10/611,918

Examiner: H. SHAKERI

Filed: July 3, 2003

Docket No.: 108833.01

For:

LENS MACHINING APPARATUS, LENS MACHINING METHOD, AND LENS

MEASUREMENT METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- \bowtie This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection, Notice of Allowance or other action that closes prosecution (e.g., Quayle Action).
 - I hereby certify that each item of information contained in this \bowtie Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR $\S 1.97(e)(1)$.
- Each item of information contained in this Information Disclosure Statement was 冈 cited in a communication from a foreign patent office in a counterpart application, and this communication was not received by any individual designated in §1.56(c) more than thirty days prior to the filing of this Information Disclosure Statement.
- \boxtimes One or more reference cited herein was cited in a counterpart foreign application. An English language version of the foreign Office Action is attached for the Examiner's information. See References 1 and 2.

- 4. An English language Abstract of one or more non-English language reference is attached. See Reference 1.
- 5. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy. See Reference 1.
- 6. JP 58-106112 and JP 09-309052 are not disclosed herein because these references were made of record in the Information Disclosure Statement filed July 3, 2003.

Respectfully submitted,

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Date: May 9, 2007

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Date: May 9, 2007